

TAPERED AMPLIFIER

GaAs Semiconductor Laser Diode



General Product Information

| Product | Application |
|--------------------------|--------------|
| 850 nm Tapered Amplifier | Spectroscopy |
| C-Mount Package | |
| | |
| | |

Absolute Maximum Ratings

| | Symbol | Unit | min | typ | max |
|---------------------------------|-----------|------|-----|-----|-----|
| Storage Temperature | T_S | °C | -40 | | 85 |
| Operational Temperature at Case | T_C | °C | 0 | | 50 |
| Forward Current | I_F | A | | | 1.7 |
| Reverse Voltage | V_R | V | | | 0 |
| Output Power | P_{opt} | W | | | 0.6 |

Recommended Operational Conditions

| | Symbol | Unit | min | typ | max |
|---------------------------------|-------------|------|-----|-----|-----|
| Operational Temperature at Case | T_C | °C | 5 | | 40 |
| Forward Current | I_F | A | | | 1.5 |
| Input Power | P_{input} | mW | 10 | | 50 |
| Output Power | P_{opt} | W | | | 0.5 |

Characteristics at $T_{LD} = 25\text{ °C}$ at Begin Of Life

| Parameter | Symbol | Unit | min | typ | max |
|--|-----------------|---------------|-----|------|-----|
| Center Wavelength | λ_c | nm | 840 | 850 | 860 |
| Gain Width (FWHM) | $\Delta\lambda$ | nm | | 30 | |
| Temperature Coefficient of Wavelength | $d\lambda / dT$ | nm / K | | 0.3 | |
| Amplification | P_{opt} | dB | | 10 | |
| Operational Current @ $P_{opt} = 0.5\text{ W}$ | $I_{op\ Gain}$ | A | | | 1.5 |
| Output Power @ $I_F = 1.5\text{ A}$ | P_{opt} | W | 0.5 | | |
| Cavity Length | L | μm | | 2750 | |



non condensing
 non condensing
 Stress in excess of the Absolute Maximum Ratings can cause permanent damage to the device. Operation at the Absolute Maximum Rating for extended periods of time can adversely affect the device reliability and may lead to reduced operational life.

Measurement Conditions / Comments
 non condensing
 with proper injection from a seed laser

Measurement Conditions / Comments
 see images on page 4
 with proper injection from a seed laser

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Characteristics at T_{amb} 25 °C at Begin Of Life cont'd

| Parameter | Symbol | Unit | min | typ | max |
|---------------------------------|------------------|------------|-----|-----|-----|
| Input Aperture (at rear side) | d_{input} | μm | | 3 | |
| Output Aperture (at front side) | d_{output} | μm | | 190 | |
| Astigmatism | A | μm | 500 | 600 | 700 |
| Divergence parallel (FWHM) | $\Theta_{ }$ | $^{\circ}$ | | 14 | |
| Divergence perpendicular (FWHM) | Θ_{\perp} | $^{\circ}$ | | 28 | |
| Polarization | | | | TE | |

| Measurement Conditions / Comments |
|------------------------------------|
| depending on operating conditions |
| E field parallel to junction plane |

EYP-TPA-0850-00500-3006-CMT03-0000

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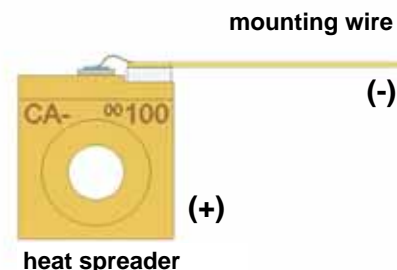
Package Dimensions

| Parameter | Symbol | Unit | min | typ | max |
|--------------------------|--------|------|------|------|------|
| Height of Emission Plane | h | mm | 7.05 | 7.20 | 7.35 |
| C-Mount Thickness | t | mm | | 2.75 | |

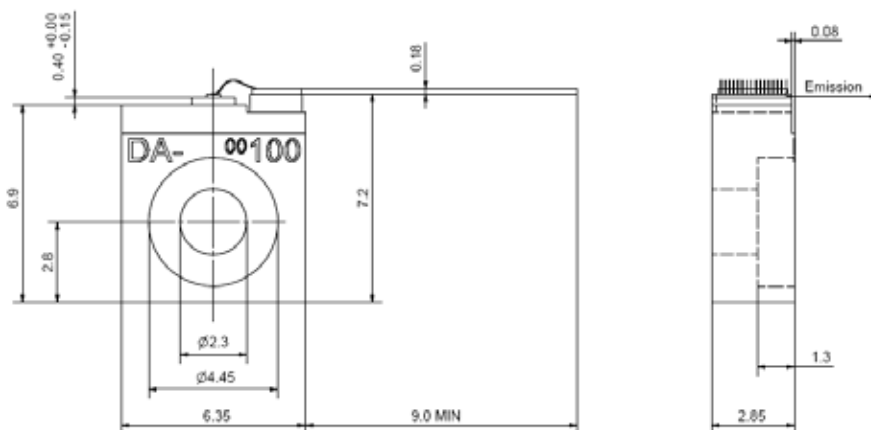
Measurement Conditions / Comments

Package Pinout

| | |
|-------------|---------------|
| Cathode (-) | Mounting Wire |
| Anode (+) | Housing |



Package Drawings



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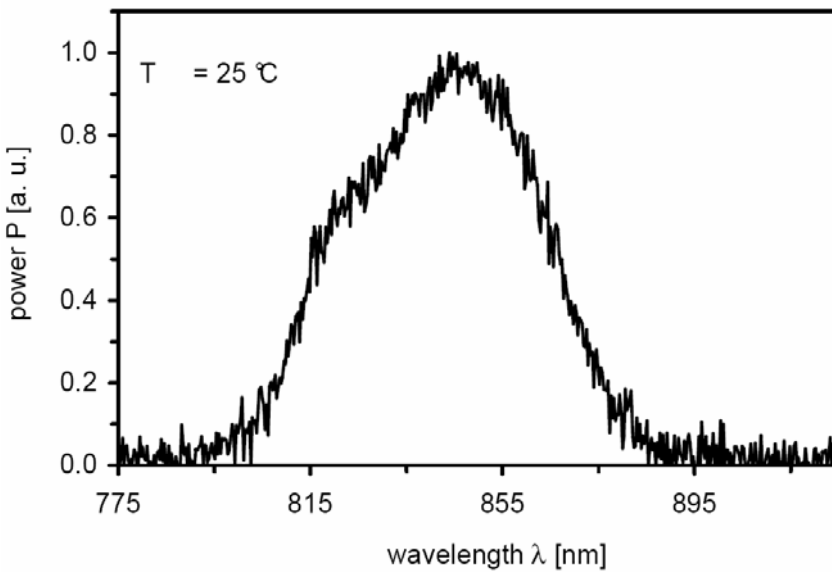
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Typical Measurement Results

Spectrum measured w/o injection:



Performance figures, data and any illustrative material provided in this specification are typical and must be specifically confirmed in writing by eagleyard Photonics before they become applicable to any particular order or contract. In accordance with the eagleyard Photonics policy of continuous improvement specifications may change without notice.

Ordering Information:

800 Village Walk #316
Guilford, CT 06437
Ph: 203-401-8093
Email orders to: sales@xsoptix.com
Fax orders to: 800-878-7282

Unpacking, Installation and Laser Safety

Unpacking the laser diodes should only be done at electrostatic safe workstations (EPA). Though protection against electro static discharge (ESD) is implemented in the laser package, charges may occur at surfaces. Please store this product in its original package at a dry, clean place until final use. During device installation, ESD protection has to be maintained.

The TPA diode type is known to be sensitive against thermal stress. It should not be operated without appropriate injection from a seed laser. Operating at moderate temperatures on proper heat sinks will contribute to a long lifetime of the diode.

The laser emission from this diode is close to the invisible infrared region of the electromagnetic spectrum. Avoid direct and/or indirect exposure to the free running beam. Collimating the free running beam with optics as common in optical instruments will increase threat to the human eye.

Each laser diode will come with an individual test protocol verifying the parameters given in this document.

Laser Emission

**INVISIBLE LASER RADIATION
AVOID EYE OR SKIN EXPOSURE
TO DIRECT OR SCATTERED RADIATION
CLASS 4 LASER PRODUCT**

WAVELENGTH **850 nm**
MAX. LASER POWER **0.6 W**

IEC 60825-1

DANGER

**INVISIBLE LASER RADIATION
AVOID EYE OR SKIN EXPOSURE TO
DIRECT OR SCATTERED RADIATION**

GaAs SEMICONDUCTOR LASER DIODE
0.6 mW MAX OUTPUT AT 850 nm
CLASS IV LASER PRODUCT

Complies with 21 CFR 1040.10 and 1040.40